

Notice of References Cited	Application/Control No. 10/517,537	Applicant(s)/Patent Under Reexamination VAN BEEK ET AL.	
	Examiner Nguyen Tran	Art Unit 2838	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,113,128	05-1992	Ohara et al.	320/160
*	B	US-5,115,182	05-1992	Ehmke et al.	320/136
*	C	US-4,513,238	04-1985	Orban, John M.	320/154
*	D	US-4,297,630	10-1981	Mullersman, Ferdinand H.	320/150
*	E	US-5,986,433	11-1999	Peele et al.	320/125
*	F	US-6,304,061	10-2001	Toya, Shoichi	320/134
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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